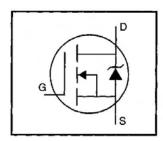
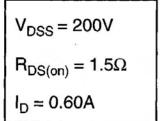
# International Rectifier

# IRFD210PbF

#### HEXFET® Power MOSFET

- Dynamic dv/dt Rating
- Repetitive Avalanche Rated
- For Automatic Insertion
- End Stackable
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Lead-Free

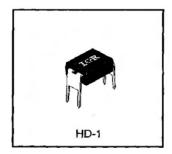




## Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The 4-pin DIP package is a low cost machine-insertable case style which can be stacked in multiple combinations on standard 0.1 inch pin centers. The dual drain serves as a thermal link to the mounting surface for power dissipation levels up to 1 watt.



## **Absolute Maximum Ratings**

	Parameter	Max.	Units	
∫ <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10 V 0.60			
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10 V 0.38		A	
l <sub>DM</sub>	Pulsed Drain Current ①	4.8		
P <sub>D</sub> @ T <sub>C</sub> = 25°C	Power Dissipation	1.0	W	
	Linear Derating Factor	0.0083	W/°C	
V <sub>GS</sub>	Gate-to-Source Voltage	±20	V	
Eas	Single Pulse Avalanche Energy ②	79	mJ	
lar	Avalanche Current ①	0.60	A	
EAR	Repetitive Avalanche Energy ①	0.10	mJ	
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns	
Tj Tstg	Operating Junction and Storage Temperature Range	-55 to +150	°C	
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)		

### **Thermal Resistance**

	Parameter	Min.	Тур.	Max.	Units
Reja	Junction-to-Ambient	·	_	120	°C/W

## Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Test Conditions		
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	200	_	_	٧	V <sub>GS</sub> =0V, I <sub>D</sub> = 250μA		
ΔV <sub>(BR)DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temp. Coefficient	1 —	0.30	_	V/°C	Reference to 25°C, I <sub>D</sub> = 1mA		
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	I -	-	1.5	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =0.36A ④		
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0	_	4.0	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> = 250μA		
g <sub>fs</sub>	Forward Transconductance	0.10	-	-	S	V <sub>DS</sub> =50V, I <sub>D</sub> =0.36A ④		
	Basis to Course Lookers Courset	<u> </u>	_	25		V <sub>DS</sub> =200V, V <sub>GS</sub> =0V		
loss	Drain-to-Source Leakage Current		_	250	μА	V <sub>DS</sub> =160V, V <sub>GS</sub> =0V, T <sub>J</sub> =125°		
1	Gate-to-Source Forward Leakage		_	100	nA	V <sub>GS</sub> =20V		
IGSS	Gate-to-Source Reverse Leakage	_		-100	nA.	V <sub>GS</sub> =-20V		
Qg	Total Gate Charge	-	_	8.2		I <sub>D</sub> =3.3A		
Qgs	Gate-to-Source Charge	_	_	1.8	nC	V <sub>DS</sub> =160V		
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge	1-	-	4.5		V <sub>GS</sub> =10V See Fig. 6 and 13 @		
t <sub>d(on)</sub>	Turn-On Delay Time	-	8.2			V <sub>DD</sub> =100V		
tr	Rise Time		17	-	ns	I <sub>D</sub> =3.3A		
t <sub>d(off)</sub>	Turn-Off Delay Time	-	14	l —	113	R <sub>G</sub> =24Ω		
t <sub>f</sub>	Fall Time	-	8.9	_		R <sub>D</sub> =30Ω See Figure 10 @		
L <sub>D</sub>	Internal Drain Inductance	_	4.0	_	nH	Between lead, 6 mm (0.25in.)		
Ls	Internal Source Inductance	_	6.0	_	1001	from package and center of die contact		
Ciss	Input Capacitance	_	140	-		V <sub>GS</sub> =0V		
Coss	Output Capacitance	<b>—</b>	53	-	рF	V <sub>DS</sub> = 25V		
C <sub>rss</sub>	Reverse Transfer Capacitance		15			f=1.0MHz See Figure 5		

#### **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Test Conditions
ls	Continuous Source Current (Body Diode)	_	_	0.60	А	MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①	-	_	4.8	^	integral reverse p-n junction diode.
V <sub>SD</sub>	Diode Forward Voltage	_	_	2.0	٧	TJ=25°C, IS=0.60A, VGS=0V
trr	Reverse Recovery Time		150	310	ns	T <sub>J</sub> =25°C, I <sub>F</sub> =3.3A
Qrr	Reverse Recovery Charge	_	0.60	1,4	μС	di/dt=100A/μs ④
ton	Forward Turn-On Time	Intrinsi	Intrinsic turn-on time is neglegible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )			

#### Notes:

- Repetitive rating; pulse width limited by max. junction temperature (See Figure 11)
- 3 I<sub>SD</sub>≤3.3A, di/dt≤70A/μs, V<sub>DD</sub>≤V(BR)DSS, T<sub>J</sub>≤150°C
- ②  $V_{DD}$ =50V, starting  $T_{J}$ =25°C, L=82mH  $R_{G}$ =25 $\Omega$ ,  $I_{AS}$ =1.2A (See Figure 12)
- ④ Pulse width ≤ 300 µs; duty cycle ≤2%.

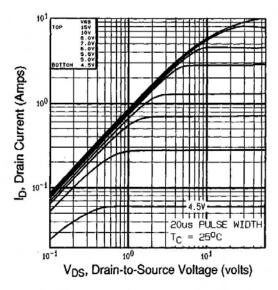


Fig 1. Typical Output Characteristics, Tc=25°C

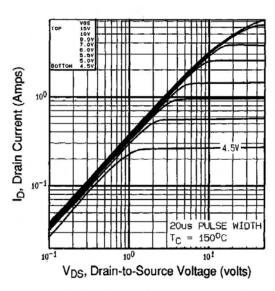


Fig 2. Typical Output Characteristics, T<sub>C</sub>=150°C

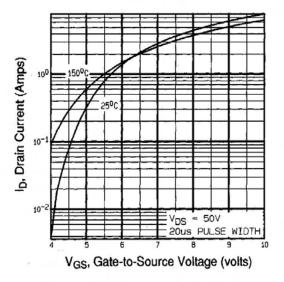


Fig 3. Typical Transfer Characteristics

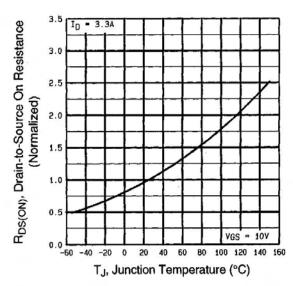


Fig 4. Normalized On-Resistance Vs. Temperature

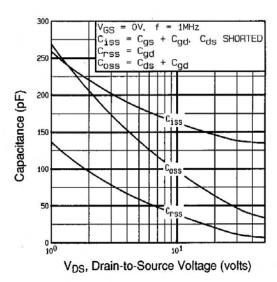


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

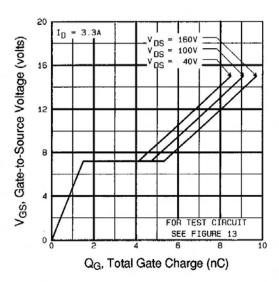


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

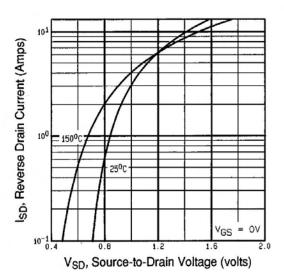


Fig 7. Typical Source-Drain Diode Forward Voltage

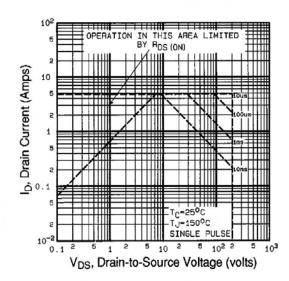


Fig 8. Maximum Safe Operating Area

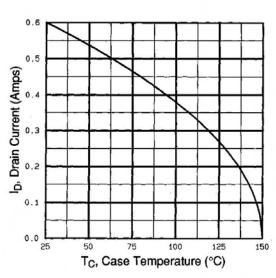


Fig 9. Maximum Drain Current Vs. Case Temperature

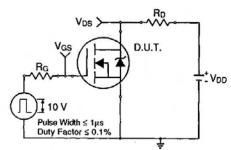


Fig 10a. Switching Time Test Circuit

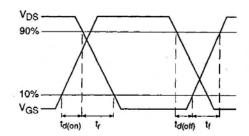


Fig 10b. Switching Time Waveforms

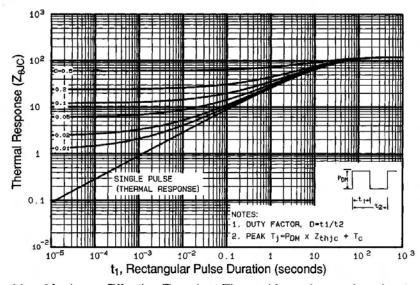


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

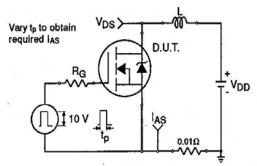


Fig 12a. Unclamped Inductive Test Circuit

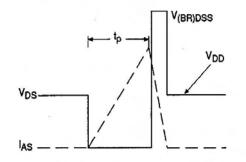


Fig 12b. Unclamped Inductive Waveforms

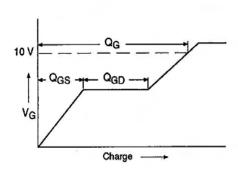


Fig 13a. Basic Gate Charge Waveform

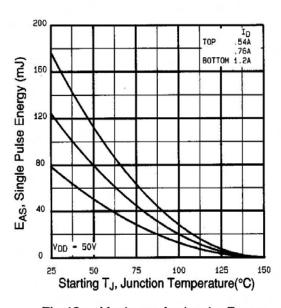


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

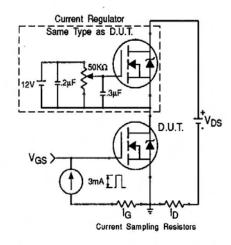
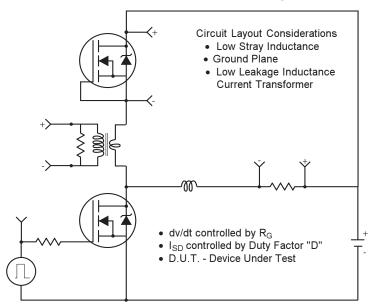
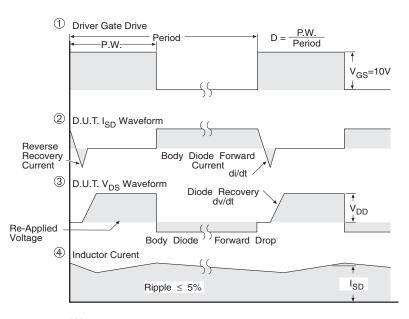


Fig 13b. Gate Charge Test Circuit

## Peak Diode Recovery dv/dt Test Circuit



- \* Reverse Polarity for P-Channel
- \*\* Use P-Channel Driver for P-Channel Measurements



\*\*\*  $V_{GS}$  = 5.0V for Logic Level and 3V Drive Devices

Fig -14 For N Channel HEXFETS

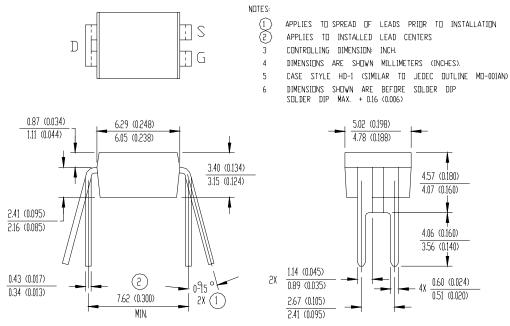
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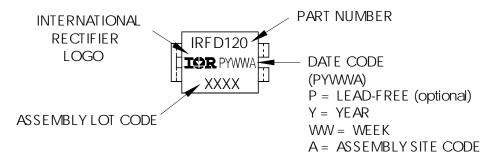
# Hexdip Package Outline

Dimensions are shown in millimeters (inches)



## Hexdip Part Marking Information

EXAMPLE: THIS IS AN IRFD120



Data and specifications subject to change without notice.



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